

1     ABSTRACT OF THE DISCLOSURE

          A semiconductor testing device is used for  
testing a semiconductor device which has at least one  
spherical connection terminal. The testing device  
5     includes an insulating substrate having an opening  
formed therein at a position corresponding to the  
position of the spherical connection terminal, and a  
contact member, formed on the insulating substrate,  
including a connection portion which is connected with  
10    the spherical connection terminal, at least the  
connection portion being deformable and extending into  
the opening.

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